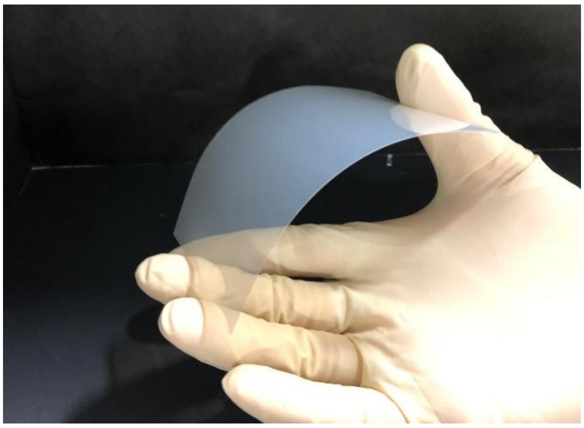

Fig1: Aluminosilicate thin film on a PEN film.

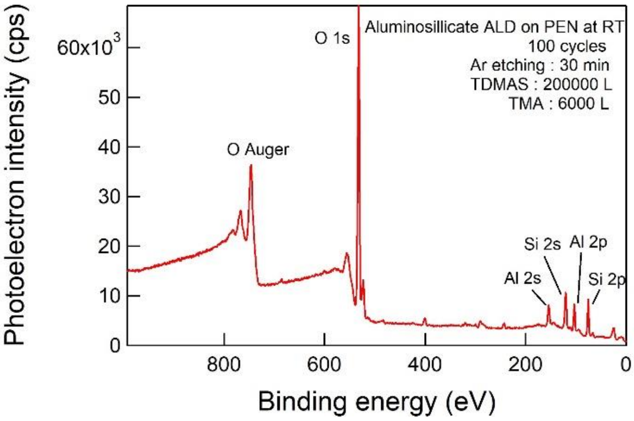

Fig2: XPS wide scan spectrum obtained from the RT deposited aluminosilicate.